Search Notes

Application/Control No.	Applicant(s)/Pate Reexamination	nt under	
10/798,378	ANACLERIO ET AL.		
Examiner	Art Unit		
Tan V. Mai	2193	•	

	SEARCHED				
Class	Subclass	Date	Examiner		
708	819	6/1/2007	MAI		
	!				
,					
		•			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		-		
				
	<u> </u>		1	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	6/1/2007	MAI	
,			
·			